

Application/Control No.	Applicant(s)/Pate Reexamination	ent under
10/616,492	LEE, YAO-SHE	NG
Examiner	Art Unit	

1765

Binh X. Tran

	SEAR	CHED	
Class	Subclass	Date	Examiner
216	58	5/25/2005	131
216	63	5/25/2005	M
216	67	5/25/2005	M
216	68	5/25/2005	35
216	74	5/25/2005	91

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
			-	
	<u> </u>			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Search keywords and inventor's name using EAST	5/25/2005	BT		
				